Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination NAKAYAMA ET AL.		
10/640,609			
Examiner	Art Unit		
Auna S. Moe	2618		

	SEAR	CHED	
Class	Subclass	Date	Examiner
348	223.1	11/11/2006	ASM I
	224.1		
	225.1		
	228.1		
348	655	11/13/2006	ASM

TMI	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
EAST searched		11/11/2006	ASM	
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